

TECHNICAL REPORT



Equipment for general lighting purposes – EMC immunity requirements– Part 1: An objective light flickermeter and voltage fluctuation immunity test method

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

EQUIPMENT FOR GENERAL LIGHTING PURPOSES – EMC IMMUNITY REQUIREMENTS–

Part 1: An objective light flickermeter and voltage fluctuation immunity test method

FOREWORD

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The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a Technical Report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

IEC TR 61547-1, which is a Technical Report, has been prepared by technical committee 34: Lamps and related equipment.

This second edition cancels and replaces the first edition published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the title of Part 1 has been changed to reflect the more general application of the objective flickermeter;
- b) the specific voltage fluctuation immunity test method has been extended for lighting equipment rated for 120 V AC and 230 V AC, 50 Hz and 60 Hz.

The text of this Technical Report is based on the following documents:

Draft TR	Report on voting
34/387/DTR	34/398A/RVDTR

Full information on the voting for the approval of this Technical Report can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61547 series, published under the general title *Equipment for general lighting purposes – EMC immunity requirements*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION

The fast rate at which solid state light (SSL) sources can change their intensity is one of the main drivers behind the revolution in the lighting world and applications of lighting. Linked to the fast rate of the intensity change is a direct transfer of the modulation of the driving current, both intended and unintended, to a modulation of the luminous output. This light modulation can give rise to changes in the perception of the environment. While in some very specific entertainment, scientific or industrial applications, a change of perception due to light modulation is desired, for most everyday applications and activities the change is detrimental and undesired. The general term used for these changes in the perception of the environment is “temporal light artefacts” (TLAs) and these can have a large influence on the judgment of the light quality. Moreover, the visible modulation of light can lead to a decrease in performance, increased fatigue as well as acute health problems like epileptic seizures and migraine episodes [18][19]¹.

Different terms exist to describe the different types of TLAs that may be perceived by humans. The term ‘flicker’ refers to light variation that may be directly perceived by an observer. ‘Stroboscopic effect’ is an effect which may become visible for an observer when a moving or rotating object is illuminated (CIE TN 006:2016[22]).

Possible causes for light modulation of lighting equipment that may give rise to flicker or stroboscopic effect are:

- AC supply combined with light source technology and its driver topology;
- dimming technology of externally applied dimmers or internal light level regulators;
- mains voltage fluctuations caused by electrical apparatus connected to the mains (conducted electromagnetic disturbances) or intentionally applied for mains-signalling purposes.

Lighting products that show unacceptable flicker or stroboscopic effect are considered as poor quality lighting.

This document provides an objective light flickermeter and a method for testing the immunity of lighting equipment against mains voltage fluctuations caused by electrical apparatus connected to the mains at levels that are allowed through IEC 61000-3-3.

Flicker perception, as well as IEC 61000-3-3 and IEC 61000-4-15, the associated standards for voltage fluctuations and flickermeter, are based on the 60 W incandescent lamp. As a result of the phasing out of incandescent lamps and the widespread introduction of alternative lighting equipment technologies, a new reference lamp was considered. It has been demonstrated that new lighting technologies are in general less but sometimes also more sensitive to supply voltage fluctuations than the current 60 W incandescent lamp. A CIGRE working group has assessed the impact of new lighting technologies on the existing flicker standards [17]. For the moment, the present flicker sensitivity curve of IEC 61000-3-3 remains as the reference. However, because of the increased diversity of sensitivity of lighting equipment to voltage fluctuations, there is a future need for a voltage-fluctuation immunity test specifically for lighting equipment. In this way, the full EMC approach (Figure 1) is introduced for flicker, i.e. with a view to limiting voltage fluctuations caused by equipment connected to the grid, and in addition to establishing a minimum level of flicker immunity of lighting equipment against these voltage fluctuations.

This document will allow the lighting industry to gain experience in flicker immunity test methods. Results of actual tests will be reported in a separate IEC Technical Report. Based on the experience gained on this immunity test method, the adoption of a similar test to be applied for IEC 61547, the immunity standard for lighting equipment, will be considered.

¹ Numbers in square brackets refer to the Bibliography.

EQUIPMENT FOR GENERAL LIGHTING PURPOSES – EMC IMMUNITY REQUIREMENTS –

Part 1: An objective light flickermeter and voltage fluctuation immunity test method

1 Scope

This part of IEC 61547 describes an objective light flickermeter, which can be applied for, amongst others, the following purposes:

- testing the intrinsic performance of all lighting equipment without voltage fluctuations;
- testing the immunity performance of lighting equipment against (unintentional) voltage fluctuation disturbance on the AC power port;
- testing the immunity performance of lighting equipment against intentional voltage fluctuation on the AC power port arising for example from ripple control systems.

The object of this document is to establish a common and objective reference for evaluating the performance of lighting equipment in terms of illuminance flicker. Temporal changes in the colour of light (chromatic flicker) are not considered in this test.

This method can be applied to lighting equipment which is within the scope of IEC technical committee 34, such as lamps and luminaires, intended for connection to a low voltage electricity supply. Independent auxiliaries such as drivers can also be tested by application of a representative light source to that auxiliary.

The objective light flickermeter and voltage fluctuation immunity method described in this document are based on the IEC 61000-3-3 standard for voltage fluctuation limits and the flickermeter standard IEC 61000-4-15.

The objective light flickermeter described in this document can be applied to objectively assess flicker of lighting equipment that is powered from any type of source, AC mains, DC mains, battery fed or fed through an external dimmer. The specific voltage fluctuation immunity test method described in this document applies to lighting equipment rated for 120 V AC and 230 V AC, 50 Hz and 60 Hz.

NOTE The principle of the method can be applied for other nominal voltage and frequency ratings.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61000-3-3:2013, *Electromagnetic compatibility (EMC) – Part 3-3: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16 A per phase and not subject to conditional connection*

IEC 61000-4-15:2010, *Electromagnetic compatibility (EMC) – Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications*